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PMIC N/A STANDARDIZED MILITARY DRAWING THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE AMSC N/A	PREPARED BY <i>Rick C. Offin</i> CHECKED BY <i>Charles E. Bosore</i> APPROVED BY <i>[Signature]</i> DRAWING APPROVAL DATE 04 DECEMBER 1989 REVISION LEVEL	DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 MICROCIRCUIT, LINEAR, QUAD, SPST JFET, ANALOG SWITCH, MONOLITHIC SILICON <table style="width: 100%;"> <tr> <td style="width: 15%;">SIZE A</td> <td style="width: 25%;">CAGE CODE 67268</td> <td style="width: 60%;">5962-89669</td> </tr> <tr> <td colspan="2">SHEET</td> <td style="text-align: center;">1</td> </tr> </table>	SIZE A	CAGE CODE 67268	5962-89669	SHEET		1
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DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:

5962-89669	01	E	X
Drawing number	Device type (1.2.1)	Case outline (1.2.2)	Lead finish per MIL-M-38510

1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type	Generic number	Circuit function
01	SW-06B	Quad SPST JFET analog switch

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter	Case outline
E	D-2 (16-lead, .840" x .310" x .200"), dual-in-line package
2	C-2 (20-terminal, .358" x .358" x .100"), square chip carrier package

1.3 Absolute maximum ratings.

V+ supply to V- supply	- - - - -	36 V dc
V+ supply to ground	- - - - -	36 V dc
Logic input voltage range	- - - - -	(-4 V or V- supply) to V+ supply
Analog input voltage range continuous	- - - - -	V- supply to V+ supply +20 V dc
Maximum current through any pin including switch	- - - - -	30 mA
Storage temperature range	- - - - -	-65°C to +150°C
Power dissipation (Pd):		
Case E	- - - - -	900 mW
Case 2	- - - - -	500 mW
Lead temperature (soldering, 60 seconds)	- - - - -	+300°C
Maximum junction temperature range (Tj)	- - - - -	+150°C
Thermal resistance, junction-to-case (θJC)	- - - - -	See MIL-M-38510, appendix C
Thermal resistance, junction-to-ambient (θJA):		
Case E	- - - - -	91°C/W max
Case 2	- - - - -	110°C/W max

1.4 Recommended operating conditions.

Positive supply voltage (V+)	- - - - -	+15 V dc
Negative supply voltage (V-)	- - - - -	-15 V dc
Ambient operating temperature range (TA)	- - - - -	-55°C to +125°C
High input voltage (VIH)	- - - - -	2.0 V dc
Low input voltage (VIL)	- - - - -	0.8 V dc

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2. APPLICABLE DOCUMENTS

2.1 Government specification, standard, and bulletin. Unless otherwise specified, the following specification, standard, and bulletin of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

BULLETIN

MILITARY

MIL-BUL-103 - List of Standardized Military Drawings (SMD's).

(Copies of the specification, standard, and bulletin required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.2 Truth table. The truth table shall be as specified on figure 2.

3.2.3 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full ambient operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in MIL-BUL-103 (see 6.6 herein).

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C < T _A < +125°C V _S = ±15 V, V _{IH} = 2 V, V _{IL} = 0.8 V unless otherwise specified	Group A subgroups	Limits		Unit
				Min	Max	
Positive supply current	I ₊	All switches OFF	1		6	mA
			2, 3		9	
Negative supply current	I ₋	All switches OFF	1		-5.0	mA
			2, 3		-7.5	
Ground current	I _G	All switches OFF or ON	1		4	mA
			2, 3		6	
Logic "0" input current	I _{IL}	V _{IN} = 0.8 V	1		5	μA
			2, 3		10	
Logic "1" input current <u>1/</u>	I _{IH}	V _{IN} = 2 V to 15 V	1		5	μA
			2, 3		10	
"ON" resistance	R _{ON}	V _S = ±10 V, I _S = 1 mA	1		80	Ω
			2, 3		110	
Delta R _{ON} vs V _A	delta R _{ON}	V _S = ±10 V, I _S = 1 mA	1		15	%
R _{ON} match between switches <u>2/</u>	R _{ON} (match)	V _S = 0 V, I _S = 100 μA	1		10	%
			2, 3		20	
Logic "1" input voltage <u>3/</u>	V _{IH}		1, 2, 3	2.0		V
Logic "0" input voltage <u>3/</u>	V _{IL}		1, 2, 3		0.8	V
Analog voltage range <u>3/</u>	V _A	I _S = 1 mA	1, 2, 3	±10		V
Analog current range <u>4/</u>	I _A	V _S = ±10 V <u>5/</u>	1	10		mA
			2, 3	7		
Source current switches OFF	I _S (OFF)	V _S = 10 V, V _D = -10 V	1		2	nA
			2, 3		60	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C < T _A < +125°C V _S = +15 V, V _{IH} = 2 V, V _{IL} = 0.8 V unless otherwise specified	Group A subgroups	Limits		Unit
				Min	Max	
Drain current switches OFF	I _D (OFF)	V _S = 10 V, V _D = -10 V	1		2	nA
			2, 3		60	
Source current switch ON	I _S (ON) +	V _S = V _D = ±10 V	1		2	nA
	I _D (ON)		2		100	
Turn-on-time	t _{ON}	V _S = -5 V, R _L = 1 kΩ C _L = 30 pF	9		500	ns
			6/ 10, 11		900	
Turn-off-time	t _{OFF}	V _S = -5 V, R _L = 1 kΩ C _L = 30 pF	9		400	ns
			6/ 10, 11		500	
Source capacitance	C _S (OFF)	V _S = 0 V See 4.3.1c	4		7.0	pF
Drain capacitance	C _D (OFF)	V _S = 0 V See 4.3.1c	4		5.5	pF
Channel "ON" capacitance	C _D (ON) and C _S (ON)	V _S = V _D = 0 V 5/	4		15	pF
"OFF" isolation	I _{SO} (OFF)	V _S = 5 V, R _L = 680Ω C _L = 7 pF, f = 500 kHz	4	50		dB
Crosstalk	C _T	V _S = 5 V, R _L = 680Ω C _L = 7 pF, f = 500 kHz	4	60		dB
Functional test		See 4.3.1d	7, 8			
Break-before-make time	t _{ON} - t _{OFF}		9	20		ns

See footnotes on next page.

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1/ Current tested at $V_{IN} = 2 \text{ V}$ (worst case condition).

2/ R_{ON} match specified as a percentage of $R_{average}$ where:
 $R_{average} = (R_{ON1} + R_{ON2} + R_{ON3} + R_{ON3}) / 4$

3/ V_A , V_{IH} , and V_{IL} is verified by leakage and R_{ON} tests.

4/ I_A is defined as follows: For analog currents less than or equal to $I_A \text{ min.}$ the switch channel "ON" resistance will not exceed twice the specified R_{ON} for that device grade.

5/ This parameter is derived from a calculation of "OFF" isolation test.

6/ If not be tested, shall be guaranteed to the limits specified in table I.

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.6 herein). The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.9 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).

(2) $T_A = +125^\circ\text{C}$, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

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Device type	01	
Case outlines	E	2
Terminal number	Terminal symbol	
1	IN ₁	NC
2	D ₁	IN ₁
3	S ₁	D ₁
4	GND	S ₁
5	V-	GND
6	S ₂	NC
7	D ₂	V-
8	IN ₂	S ₂
9	IN ₃	D ₂
10	D ₃	IN ₂
11	S ₃	NC
12	V+	IN ₃
13	DISABLE	D ₃
14	S ₄	S ₃
15	D ₄	V+
16	IN ₄	NC
17	-	DISABLE
18	-	S ₄
19	-	D ₄
20	-	IN ₄

FIGURE 1. Terminal connections.

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Disable input	Logic input	Switch state	
		Channels 1 AND 2	Channels 3 AND 4
0	X	OFF	OFF
1 OR NC	0	OFF	ON
1 OR NC	1	ON	OFF

NC = no connection

FIGURE 2. Truth table.

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4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 5, and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Supgroup 4 ($C_S(\text{OFF})$ and $C_D(\text{OFF})$ measurements) shall be measured only for the initial test and after process or design changes which may affect capacitance.
- d. Subgroups 7 and 8 shall include verification of the truth table.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125^\circ\text{C}$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	1
Final electrical test parameters (method 5004)	1*,2,3,7,8
Group A test requirements (method 5005)	1,2,3,4,7,8, 9,10**,11**
Groups C and D end-point electrical parameters (method 5005)	1

* PDA applies to subgroup 1.

** Subgroups 10 and 11, if not tested, shall be guaranteed to the limits specified in table I herein.

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5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).

6.4 Record of users. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DESC-ECS, telephone (513) 296-6022.

6.5 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone (513) 296-5375.

6.6 Approved source of supply. An approved source of supply is listed in MIL-BUL-103. Additional sources will be added to MIL-BUL-103 as they become available. The vendor listed in MIL-BUL-103 has agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-ECS. The approved source of supply listed below is for information purposes only and is current only to the date of the last action of this document.

Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1/</u>
5962-8966901EX	06665	SW06BY/883
5962-89669012X	06665	SW06BRC/883

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE
number

06665

Vendor name
and address

Precision Monolithics Incorporated
1500 Space Park Drive
Santa Clara, CA 95050

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